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INTRODUCTION

In view of the recent amendment made in the Patents Act, 1970 by the Patents (Amendment) Act, 2005 effective from 01st January 2005, the Official Journal of The Patent Office is required to be published under the Statute. This Journal is being published on weekly basis on every Friday covering the various proceedings on Patents as required according to the provision of Section 145 of the Patents Act 1970. All the enquiries on this Official Journal and other information as required by the public should be addressed to the Controller General of Patents, Designs & Trade Marks. Suggestions and comments are requested from all quarters so that the content can be enriched.

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(57) Abstract :
A real-time seriplane test system (106) and method for inspecting raw silk threads using AI is disclosed. The system (106) includes camera (202) and processor (204). The camera is configured to capture real-time images of test raw silk thread. Processor is configured to receive a plurality of image data sets from electronic system, pre-process plurality of image data sets for extracting a plurality of parameters, configured to store receive plurality of image data sets and plurality of parameters for training and testing test raw silk threads using Deep Learning modules, train Deep Learning modules based on receive plurality of image data sets and plurality of parameters, deploy trained Deep Learning modules for detecting defects of real-time captured image of test raw silk threads, compare real-time captured image of test raw silk threads with plurality of parameters, and provide grade based results of test raw silk threads. <>

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